



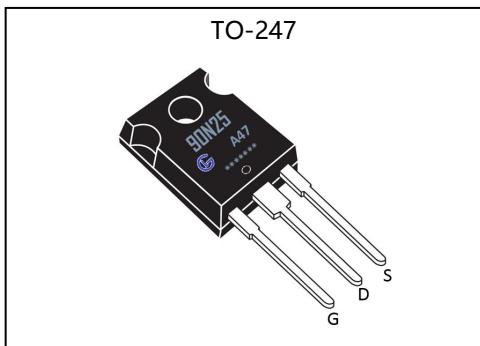
# GL90N25A47

## Silicon N-Channel Power MOSFET

### General Description:

GL90N25A47, the silicon N-channel Enhanced VDMOSFET, is obtained by the self-aligned planar Technology which reduce the conduction loss, improve switching performance and enhance the avalanche energy. The transistor can be used in various power switching circuit for system miniaturization and higher efficiency. The package form is TO-247, which accords with the RoHS standard.

$V_{DSS}(T_c=150^\circ\text{C})$	250	V
$I_D$	90	A
$P_D(T_c=25^\circ\text{C})$	960	W
$R_{DS(ON)}\text{TYP}$	25	$\text{m}\Omega$



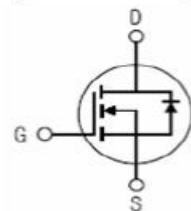
### Features:

- Fast Switching
- ESD Improved Capability
- Low Gate Charge
- Low Reverse transfer capacitances
- 100% Single Pulse avalanche energy Test

### Applications:

- Power switch circuit of POWER

Inner Equivalent Principium Chart



### Absolute ( $T_c=25^\circ\text{C}$ unless otherwise specified):

Symbol	Parameter	Rating	Units
$V_{DSS}$	Drain-to-Source Voltage	250	V
$I_D$	Continuous Drain Current	90	A
	Continuous Drain Current $T_c=100^\circ\text{C}$	70	A
$I_{DM}^{a1}$	Pulsed Drain Current( pulse width limited by $T_{JM}$ )	360	A
$V_{GS}$	Gate-to-Source Voltage	$\pm 30$	V
$E_{AS}$	Single Pulse Avalanche Energy	3500	mJ
$E_{Ar}^{a1}$	Avalanche Energy ,Repetitive	250	mJ
$I_{AR}^{a1}$	Avalanche Current	45	A
$dv/dt^{a2}$	Peak Diode Recovery $dv/dt$	5.0	V/ns
$P_D$	Power Dissipation	960	W
	Derating Factor above $25^\circ\text{C}$	7.68	$\text{W}/^\circ\text{C}$
$T_J, T_{stg}$	Operating Junction and Storage Temperature Range	150, -55 to 150	$^\circ\text{C}$
$T_L$	Maximum Temperature for Soldering	300	$^\circ\text{C}$

Caution Stresses greater than those in the "Absolute Maximum Ratings" may cause permanent damage to the device



# GL90N25A47

Silicon N-Channel Power MOSFET

## Thermal Characteristics

Symbol	Parameter	Rating	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	0.21	°C / W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	40	°C / W

**Electrical Characteristics** (T<sub>c</sub>=25°C unless otherwise specified):

OFF Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
$V_{DSS}$	Drain to Source Breakdown Voltage	$V_{GS}=0V, I_D=250\mu A$	250	--	--	V
$I_{DSS}$	Drain to Source Leakage Current	$V_{DS}=250V, V_{GS}=0V, T_a=25^{\circ}C$	--	--	1.0	$\mu A$
		$V_{DS}=200V, V_{GS}=0V, T_a=125^{\circ}C$	--	--	100	
$I_{GSS(F)}$	Gate to Source Forward Leakage	$V_{GS}=+30V$	--	--	100	nA
$I_{GSS(R)}$	Gate to Source Reverse Leakage	$V_{GS}=-30V$	--	--	-100	nA

ON Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
$R_{DS(ON)}$	Drain-to-Source On-Resistance	$V_{GS}=10V, I_D=45A$	--	25	35	mΩ
$V_{GS(TH)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu A$	2.0	--	4.0	V
$g_{fs}$	Forward Trans conductance	$V_{DS}=15V, I_D=45A$	--	50	--	S
Pulse width<380μs; duty cycle<2%.						

Dynamic Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
$C_{iss}$	Input Capacitance	$V_{GS}=0V, V_{DS}=25V$ $f=1.0MHz$	--	7500	--	pF
$C_{oss}$	Output Capacitance		--	880	--	
$C_{rss}$	Reverse Transfer Capacitance		--	180	--	

Resistive Switching Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
$t_{d(ON)}$	Turn-on Delay Time	$I_D=45A, V_{DD}=125V$ $V_{GS}=10V, R_g=25\Omega$	--	68	--	ns
$t_r$	Rise Time		--	120	--	
$t_{d(OFF)}$	Turn-Off Delay Time		--	485	--	
$t_f$	Fall Time		--	145	--	
$Q_g$	Total Gate Charge	$I_D=45A, V_{DD}=125V$ $V_{GS}=10V$	--	140	--	nC
$Q_{gs}$	Gate to Source Charge		--	22	--	
$Q_{gd}$	Gate to Drain ( "Miller" )Charge		--	55	--	



# GL90N25A47

Silicon N-Channel Power MOSFET

Source-Drain Diode Characteristics						Units	
Symbol	Parameter	Test Conditions	Rating				
			Min.	Typ.	Max.		
$I_{SD}$	Continuous Source Current (Body Diode)		--	--	90	A	
$I_{SM}$	Maximum Pulsed Current (Body Diode)		--	--	360	A	
$V_{SD}$	Diode Forward Voltage	$I_S=90A, V_{GS}=0V$	--	--	1.5	V	
$t_{rr}$	Reverse Recovery Time	$I_S=90A, T_j=25^\circ C$	--	380	--	ns	
$Q_{rr}$	Reverse Recovery Charge	$dI_F/dt=100A/\mu s, V_{GS}=0V$	--	3.7	--	uC	

a1: Repetitive rating; pulse width limited by maximum junction temperature

a2:  $I_{SD}=90A, di/dt \leq 100A/\mu s, V_{DD} \leq BV_{DS}$ , Start  $T_j=25^\circ C$



# GL90N25A47

Silicon N-Channel Power MOSFET

## Characteristics Curve:

Fig. 1. Output Characteristics @  $T_J = 25^\circ\text{C}$

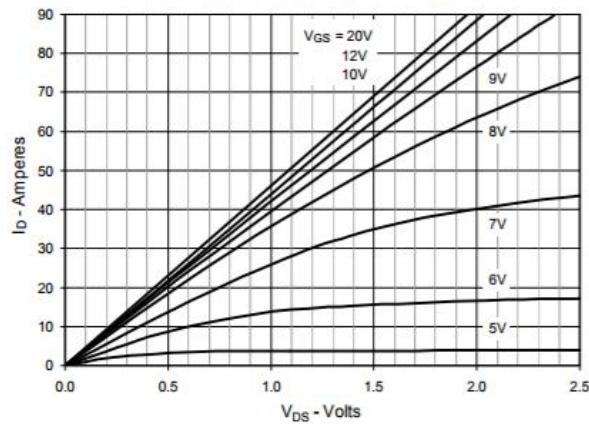


Fig. 2. Extended Output Characteristics @  $T_J = 25^\circ\text{C}$

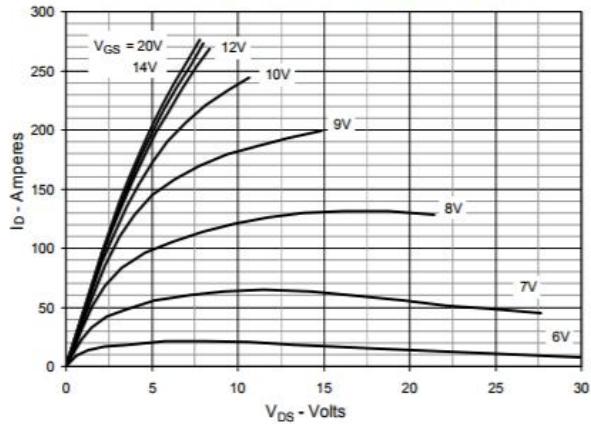


Fig. 3. Output Characteristics @  $T_J = 125^\circ\text{C}$

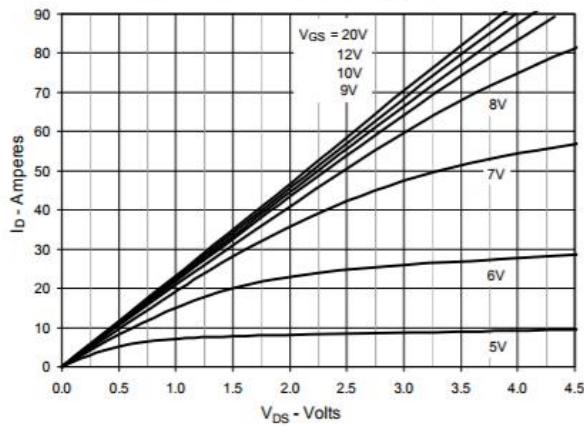


Fig. 4.  $R_{DS(on)}$  Normalized to  $I_D = 45\text{A}$  Value vs. Junction Temperature

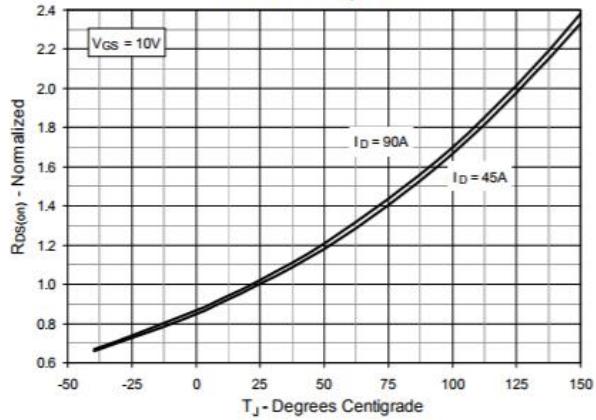


Fig. 5.  $R_{DS(on)}$  Normalized to  $I_D = 45\text{A}$  Value vs. Drain Current

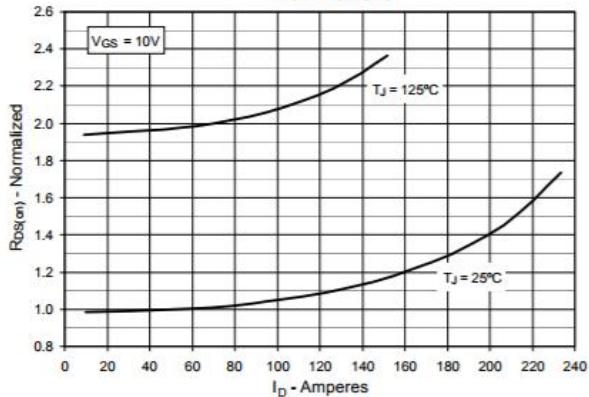
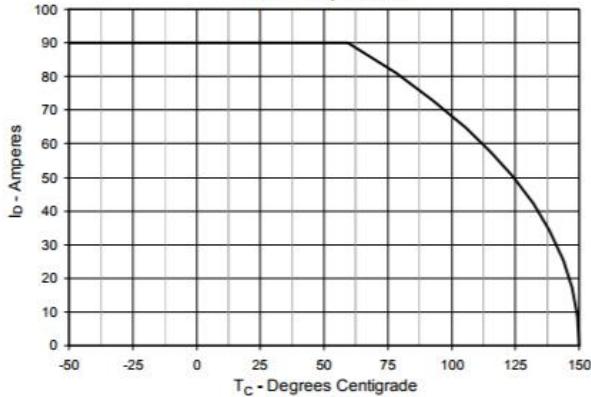


Fig. 6. Maximum Drain Current vs. Case Temperature





# GL90N25A47

Silicon N-Channel Power MOSFET

Fig. 7. Input Admittance

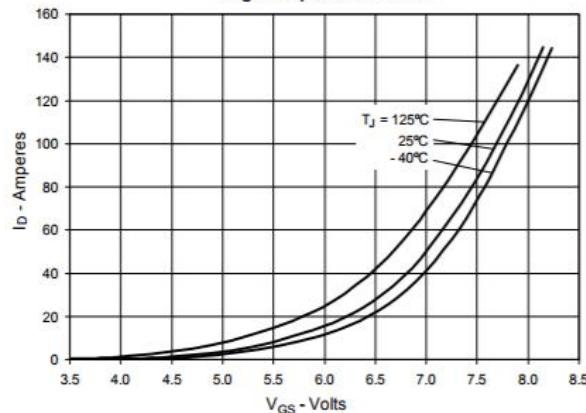


Fig. 8. Transconductance

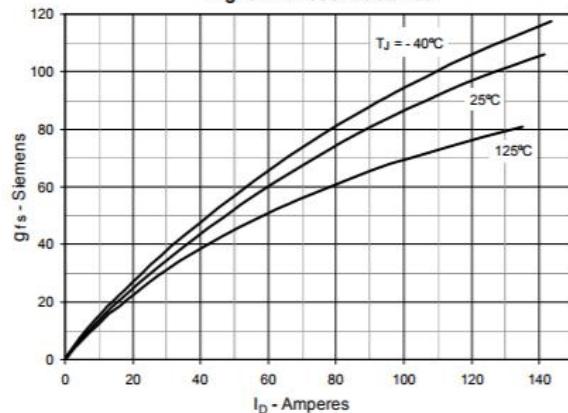


Fig. 9. Forward Voltage Drop of Intrinsic Diode

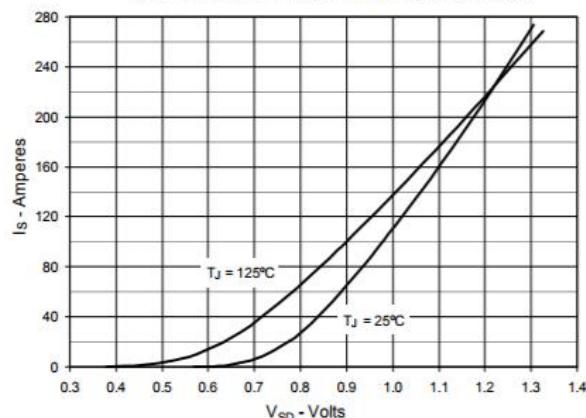


Fig. 10. Gate Charge

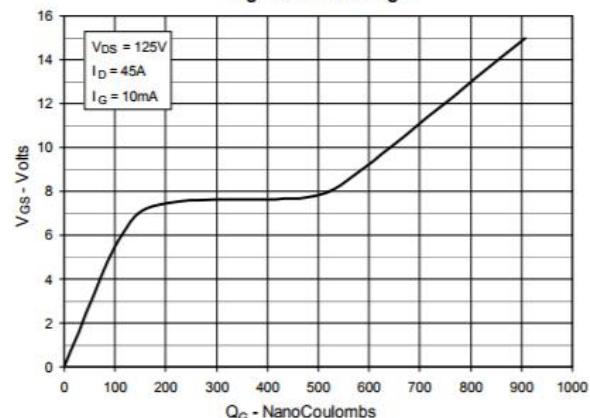


Fig. 11. Capacitance

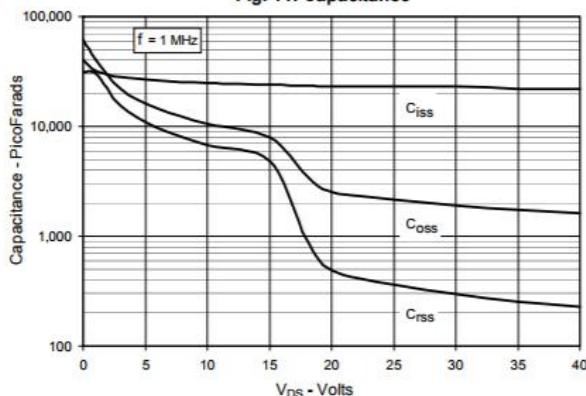
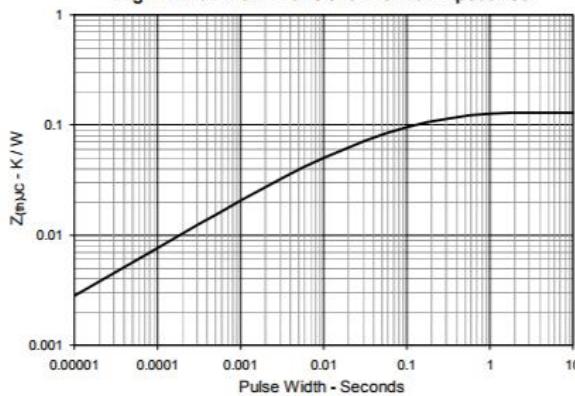


Fig. 12. Maximum Transient Thermal Impedance





# GL90N25A47

Silicon N-Channel Power MOSFET

Fig. 13. Forward-Bias Safe Operating Area  
@  $T_C = 25^\circ\text{C}$

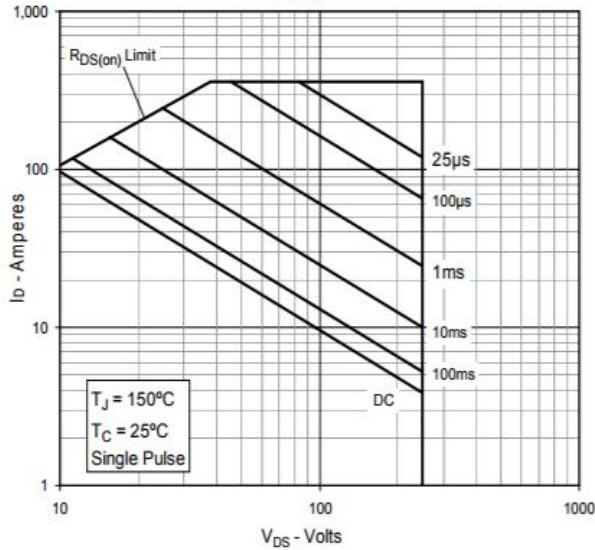


Fig. 14. Forward-Bias Safe Operating Area  
@  $T_C = 75^\circ\text{C}$

